

Theory:

When light rays are partially obstructed, they tend to show amount of bending around the obstacle which results in a pattern of illuminated and dark spots on a screen. This pattern as diffraction. This bending of light can be explain by Huygen's prenciple which states that every point on the by Huygen's prenciple which states that every point on the by that arrives at the aperture acts as a source of spherical and these secondary waves interfere on the screen to gen the diffraction pattern.

1 Diffraction of light by double slit:

$$I(\theta) = I_{\cos^2(\frac{\pi d \sin \theta}{\lambda})} \left(\frac{\sin(\beta)}{\beta}\right)^2$$

where B = Trasing

where a = wedth of each slit

d = separation b/w slits

d= mx sin(on)

Conditions for maxima: deino =  $m\lambda$ Conditions for minima: deino =  $(2m+1)\lambda$ 

where m = ±1, ±2, ±3...

In this experiment d>a,

From the positions of maxima we can find slet separation,

, Om = tanty

1				
IN	DIAN INSTITUTE			
O	AND DESCRIPTION OF THE PERSON	NO. 2380	A94 CLASS	
TI	ECHNOLOGY ROMA	NAME V	1.1.1	BATCH P15/9
1	ECHNOLOGY BOMB	Ay	hi duilas Reddy	
	HYSICS DEPT.	EXPT. No.	1	LABORATORY
P	HISICO DEFI.	DATE		
1				
Ob	servations:			
1				
not	traction by o	la de als		
N	Track of the page of	iouble sut:		
	100			
.No	Maen scale	scale reading	Total reading	Intersty
	reading (mm)	Scale reading	(mm)	(Au)
1	n	45 × 0.01 = 0.65	11.45	42.0
1		=0.45		
2	11.5	25 x 0-01 = 0-25	11 -75	31.5
		45×0-01=0-45	11-95	14.3
3.	11.5			2.6
4.	12	32x0-01=0-32	12.32	
5.	105	10 ×0-01 = 0-10	12-60	10-7
	12.5	30x0-01 = 0-30	12-80	23.6
6.	12.5		13-18	39.2
7	13	18×0-01=0-18		32-3
1		43×0.01=0.43	13.43	
8	13	(2×0.0)=0-12	18-62	20.5
9.	13.5		14-00	2.3
10.	14	7x0.01=0.07		26.6
1		18×0-01 =0-18	14.68	31-8
11.	14.5	42×0-01=0-42	14-92	
12.	14.5	9440	15.40	19
13.	15	40×0-01=0-40		
U	13			

-	INDIAN INSTITUTE					
1	OF	NO.	CI.			
1	TECHNOLOGY	NAME	CLASS	ВАТСН		
		EXPT. No.				
	PHYSICS DEPT.	DATE		LABORATORY		
	Marn Scale	Circular cold				
	reading (mm)	Circular scale reading (mm)	Total (mm)	Intersity (MA)		
	15-5	30×0·01 = 0·30	15.80	1.9		
	16-	40×0.01 = 0.40	16-40	18.5		
	16.5	12 X 0-01 = 0-12	16.62	22.6		
	10.5	40×0-01=0-40	10.90	13.3		
	10.5	10 x 0 · 01 = 10 · 6	10-60	2.6		
	10	20 X 0 · 01 = 0 · 20	10.20	17.7		
		0x0.01=0.00	10-00	30.9		
-	9.5	21x0-01=0-21	9.71	39-2		
-	19	30x0.01 > 0.30	9-30	20-4		
-	8-5	35 x0-01 = 0-35	8.40	2-3		
1		40×0.01 = 0.40	8.40	26.7		
100	1 / 0	25x0.01 = 8-25 0.25 0x0.01 = 0.00	8.00	32-6		
7		0×0-01=0-00	7.50	13.5		
1 8		10×0.01 = 0.10	7-10	1.9		
	6.8	40×0.01 = 0.40	6.90	5-3		
	2 6	30×0·01 = 0·30	6-30	24.7		

to the factor factor and

determined by d' (separation du the slits) determined by suit width a > Diffiaction envelope -> Intuference fine structure Diffraction pattern for double stit screen on detector stit LOKEY 10 Diagoan

THIN		INDIAN INSTITUTE		HHI				149
		TECHNOLOGY		NO.		CLASS		BATCH
		PHYSICS DEPT.		EXPT. N	0.		LAB	ORATORY
	So 0,	= tan (ym)						
chion with	y.	= distance of n	ith maxis	na from a	entral r	naxema		
1		tan ( 13.18-11.1	15) =	0.092°				
	01 =	tan ( 11.45 -9	1.71) =	0.093		nel .		
	$0_2 = 0_2' =$	tan (14.92-11-	00) =	0.184°				
		(070						
	dsin(	$(Om) = m\lambda$	, d=	mh sin(Om)				
	* d1 =	$= 1 \times 650 \times 10^{9}$ $= 1 \times 650 \times 10^{9}$ $= 1 \times 650 \times 10^{9}$	= 0.4	04 mm				
	di'	= 0.403 mm						
		= 0.404mm = 0.402mm						
	de'	4	. 0.404-	+0.403 +	0.404 +	0-402	= 0.40	3 mm

) Do not touch the inner surface of diffraction Precautions: 2) Avoid backlash error while moving the micronet scale on the detector. 3) Take care while handling all the equipment. 4) Avoid looking directly into the laser beam Calculations: O Double slit :-Icentral max. = 11.45 mm Jerst maxima :- 4 = 13-18 9= 9.71 second maxima :- YB = 8-00mm 42 = 4/3/ 14.92 mm 0'= 1070 mm

Diffraction pattern Intensity (MA) vs total reading (mm) SCALE - 1 cm along y-axis I'm in x-axis = 3 MA Intensity (MA) 9-5-5-5-2-2-3-8-8-5-4 0 pq)

